(DATA - BKG) vs SIGMC. MUON Zγ MCclosure EB+EE MU

N_{events}/(bin width)

underflow bin

Zγ
DD true, $\sigma_{i\eta i\eta}$ fits
DD true, I_{ch} fits

1000

100

10

1

0.1

1.8
1.6
1.4
1.2
1
0.8
0.6

20   30   40 50   100   200   300 400

P$_T^\gamma$, GeV